

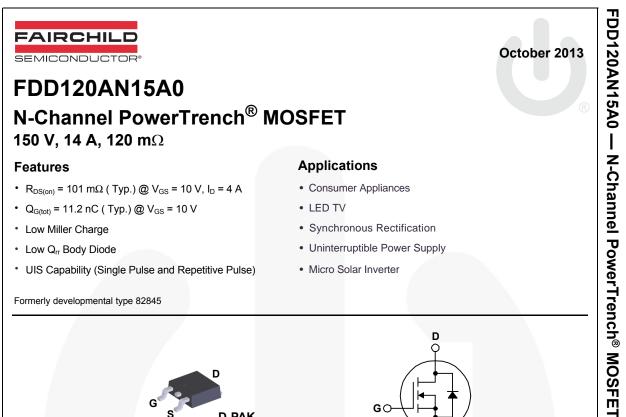
Is Now Part of



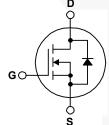
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MOSFET Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter	FDD120AN15A0	Unit	
V _{DSS}	Drain to Source Voltage	150	V	
V _{GS}	Gate to Source Voltage	±20	V	
ID	Drain Current			
	Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 10V$)	14	А	
	Continuous ($T_C = 100^{\circ}C$, $V_{GS} = 10V$)	9.7	А	
	Continuous ($T_{amb} = 25^{\circ}C$, $V_{GS} = 10V$) with $R_{\theta JA} = 52^{\circ}C/W$	2.8	А	
	Pulsed	Figure 4	А	
E _{AS}	Single Pulse Avalanche Energy (Note 1)	122	mJ	
P _D	Power dissipation	65	W	
	Derate above 25°C	0.43	W/°C	
T _J , T _{STG}	Operating and Storage Temperature	-55 to 175	°C	

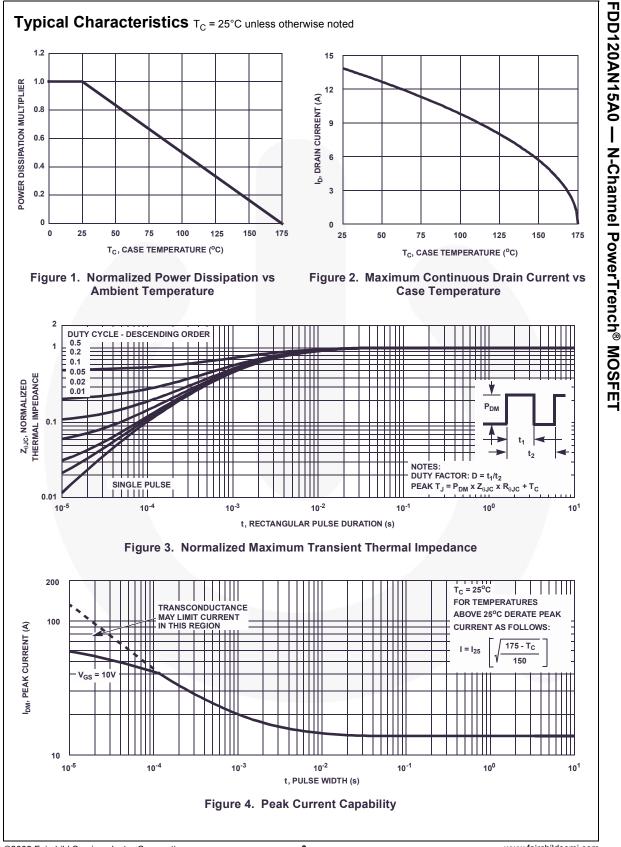
Thermal Characteristics

$R_{ extsf{ heta}JC}$	Thermal Resistance, Junction to Case, Max.	2.31	°C/W
$R_{ extsf{ heta}JA}$	Thermal Resistance, Junction to Ambient, Max.	100	°C/W
R_{\thetaJA}	Thermal Resistance, Junction to Ambient, 1in ² copper pad area, Max.	52	°C/W

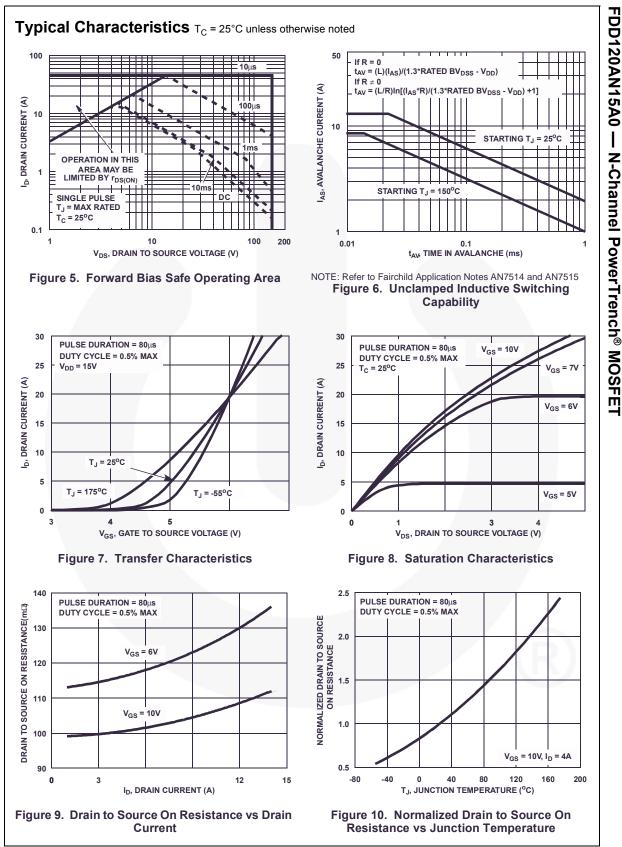
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Device MarkingDeviceFDD120AN15A0FDD120AN15A0		Package	Reel Size	Tape \	Vidth	Quar	ntity		
		FDD120AN15A0	D-PAK	330 mm	16 mm		2500 units		
Electri	cal Chara	acteristics T _C = 25°C	unless otherwis	se noted					
Symbol	I	Parameter	Test	Conditions	Min	Тур	Мах	Unit	
Off Char	racteristics	s			•			•	
		ource Breakdown Voltage	I _D = 250μA,	$V_{ab} = 0 V_{ab}$	150	-	-	V	
B _{VDSS}	Diamito S	ource breakdown vollage	$V_{DS} = 120V$		-	-	1	V	
I _{DSS}	Zero Gate	Voltage Drain Current	$V_{\rm DS} = 120V$ $V_{\rm GS} = 0V$	T _C = 150 ^o C	-	_	250	μA	
I _{GSS}	Gate to So	ource Leakage Current	$V_{GS} = \pm 20V$		-	-	±100	nA	
			65		l	1			
On Char	racteristics	6							
V _{GS(TH)}	Gate to So	ource Threshold Voltage	$V_{GS} = V_{DS},$		2	-	4	V	
			$I_D = 4A, V_{GS}$		-	0.101	0.120		
r _{DS(ON)}	Drain to S	ource On Resistance	$I_D = 2A, V_{GS}$		-	0.113	0.170	Ω	
D3(ON)			I _D = 4A, V _{GS} T _J = 175°C	, = 10V,	-	0.235	0.282		
						1			
-	c Characte								
CISS	Input Capa		V _{DS} = 25V, V	$v_{00} = 0 V$	-	770	-	pF	
C _{OSS}	Output Ca		f = 1MHz	•GS = •••,	-	85	-	pF	
C _{RSS}		ransfer Capacitance			-	17	-	pF	
Q _{g(TOT)}		Charge at 10V	$V_{GS} = 0V$ to			11.2	14.5	nC	
Q _{g(TH)}		Gate Charge	$V_{GS} = 0V$ to	2V V _{DD} = 75V	-	1.4	1.8	nC	
Q _{gs}		ource Gate Charge		$I_D = 4A$	-	3.5	-	nC	
Q _{gs2}		rge Threshold to Plateau		$I_g = 1.0 \text{mA}$	-	2.1	-	nC	
Q _{gd}	Gate to Dr	rain "Miller" Charge			-	2.6	-	nC	
Switchir	ng Charact	teristics (V _{GS} = 10V)							
t _{ON}	Turn-On T		1		-	-	33	ns	
t _{d(ON)}	Turn-On D	elay Time			-	6	-	ns	
t _r	Rise Time		V _{DD} = 75V, I	D = 4A	-	16	-	ns	
t _{d(OFF)}	Turn-Off D	elay Time	$V_{GS} = 10V,$		-	30	-	ns	
t _f	Fall Time				-	19	-	ns	
t _{OFF}	Turn-Off T	ïme			-	- /	74	ns	
	ource Diod	le Characteristics	I		•				
			$I_{SD} = 4A$		- /	-	1.25	V	
V _{SD}	Source to	Drain Diode Voltage	$I_{SD} = 2A$		-	-	1.0	V	
	Reverse R	Recovery Time	$I_{SD} = 4A, dI_{SD}/dt = 100A/\mu s$		-	-	61	ns	
t _{rr}		Recovered Charge	$I_{SD} = 4A, dI_{SD}/dt = 100A/\mu s$		-	-	109	nC	

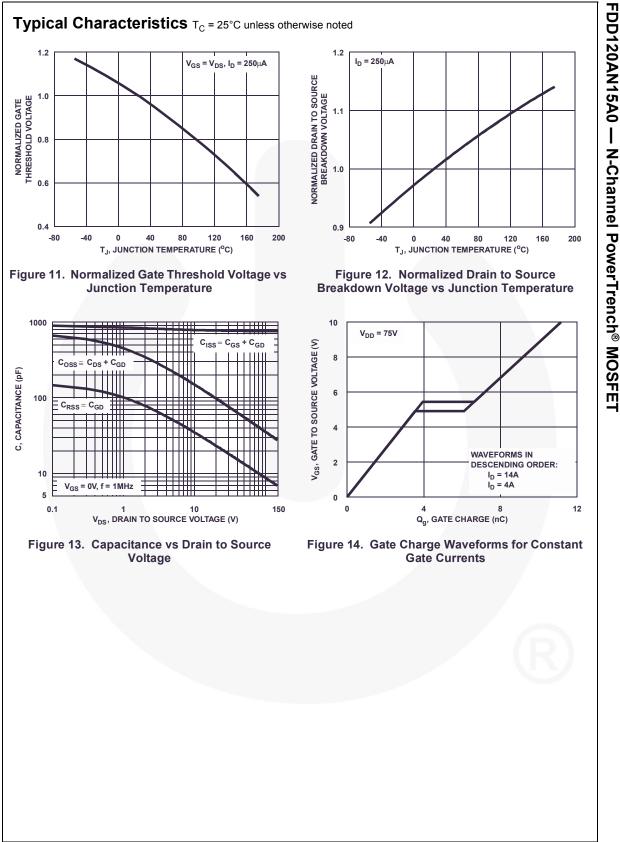
FDD120AN15A0 — N-Channel PowerTrench® MOSFET

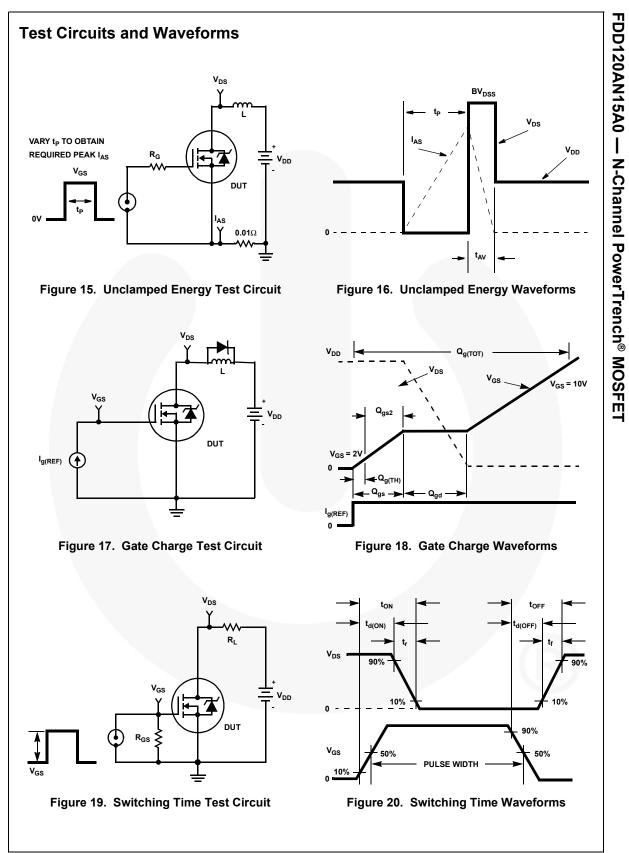


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Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, $T_A~(^oC)$, and thermal resistance $R_{\theta JA}~(^oC/W)$ must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}}$$
(EQ. 1)

In using surface mount devices such as the TO-252 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

- Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- 2. The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- 6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

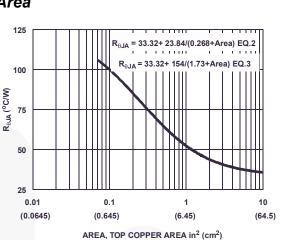
$$R_{\theta JA} = 33.32 + \frac{23.84}{(0.268 + Area)}$$
 (EQ. 2)

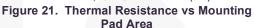
Area in Inches Squared

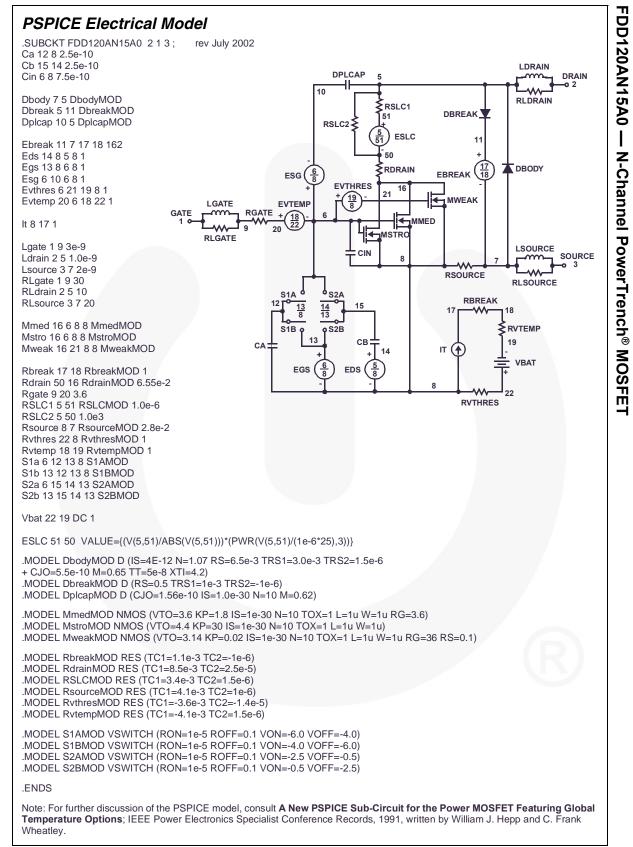
$$R_{\theta JA} = 33.32 + \frac{154}{(1.73 + Area)}$$
(EQ. 3)

Area in Centimeters Squared

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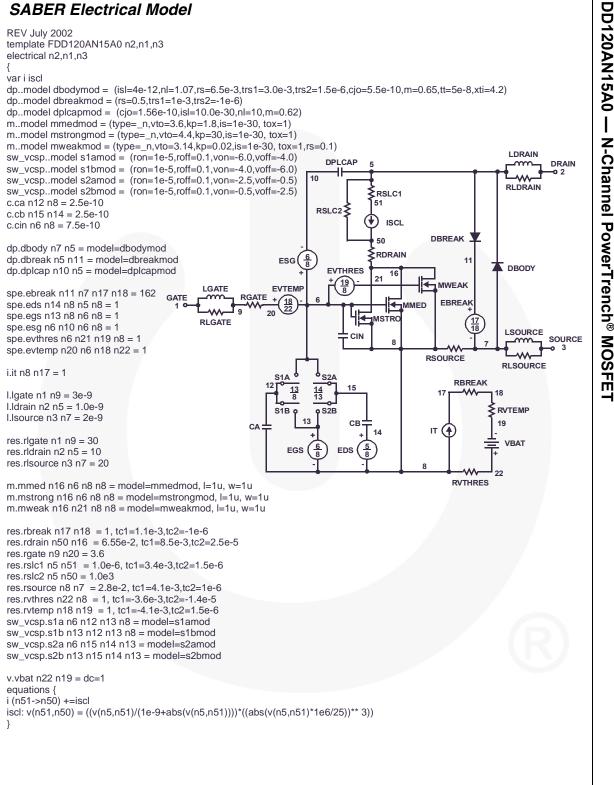




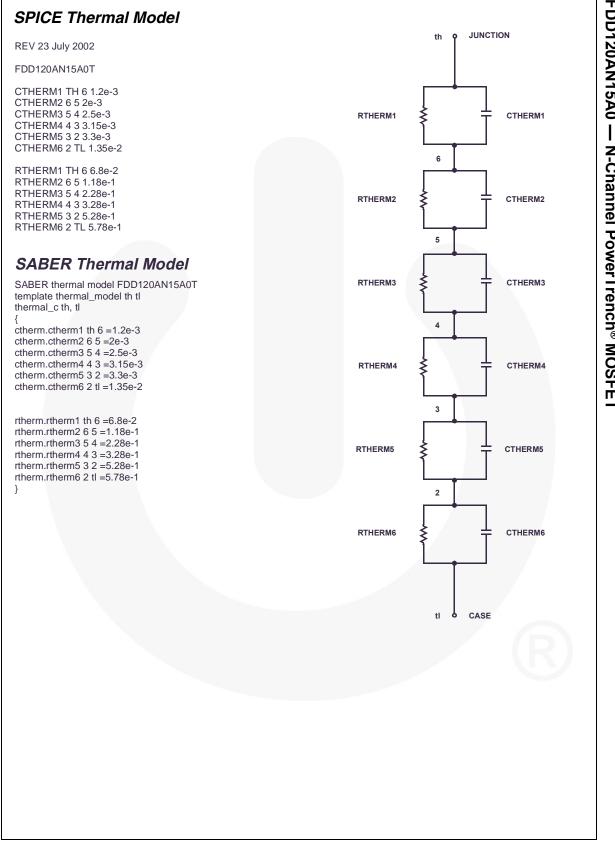


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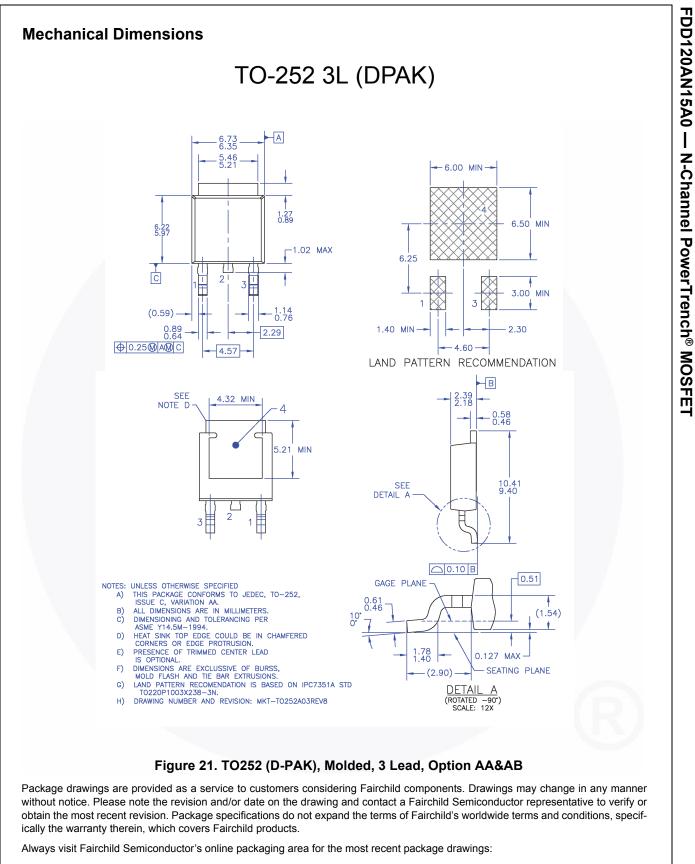
SABER Electrical Model



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Dimension in Millimeters



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